

**Search Notes**

Application/Control No.

10/825,100

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

KONDO ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	693	6/2/2006	BT
438	695	6/2/2006	BT
438	697	6/2/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search inventor's name and keywords using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	6/2/2006	BT